FOUR PROBE APPARATUS

Experiment(s):

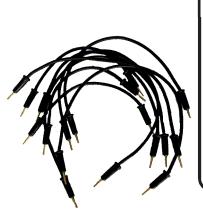
- 1. Resistivity variation with temperature for a semiconductor sample
- 2. Determination of energy gap of a semiconductor sample

(For more details, procedure & manual visit: www.kamaljeeth.net)

Reference : Lab Experiments Journal vol-11, No.1, Page-1 Lab Experiments Journal vol-10, No.4, Page-316







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Experiment setup consists:

a) Resistivity of semiconductor by four probe kit

b) Four probe arrangement & Heater

Specifications:

a) Resistivity of semiconductor by four probe kit Voltmeter: 0-200 mV Resolution: 0.1 mV Ammeter: 0-20 mA Resolution: 0.01 mA Source: Built-in constant current source with variable output current setting Internally connected voltmeter and current meters Rated Input: 220 V/50 Hz 110 V/60 Hz or Power Consumption: <200 W **Digital thermostat** Resolution: 0.1 °C Max temperature: 110 °C Set temperature: with-in <u>+</u>1 °C

b) Four probe arrangement:

Crystal: Mounted on heating element (electrically insulated) Sample: Germanium Size: 10 mm x 5 mm x 1 mm Pitch of each probe: 2 mm Heater: 100 W

(b)



KAMALJEETH INSTRUMENTS

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3 years manufacturing warranty